



WF280A
Digital Pressure Sensor

Key parameters

- Pressure range: 300 ... 1100hPa
- Package: 8-pin LGA metal-lid
Footprint: 2.0 × 2.5mm², height: 1.0mm
- Relative accuracy: 0.12 hPa, equiv. to ±1.0 m (950 ... 1050hPa@25°C)
- Absolute accuracy: typ. ±1 hPa (950 ... 1050hPa, 0...+40°C)
- Temperature coefficient offset: 1.5 Pa/K, equiv. to 12.6 cm/K (25...+40°C @ 900hPa)
- Digital interface: I²C
- Current consumption: 5.4µA @1Hz sampling rate
- Temperature range: -40...+85°C
- RoHs compliant, halogen-free

Typical applications

- Indoor navigation (floor detection, elevator detection)
- Outdoor navigation, leisure and sports applications
- Enhancement of GPS navigation
- Weather forecast
- Health care applications (e.g. spirometry)
- Vertical velocity indication (e.g. rise/sink speed)

Target devices

- Handsets such as mobile phones, tablet PCs, GPS devices
- Navigation systems
- Portable health care devices
- Home weather stations
- Flying toys
- Sport watches

Brief Description

WF280A is a high precision barometer and altimeter especially designed for consumer applications. It measures the pressure based on piezo-resistive MEMS pressure sensor.

The ultra-low power, low voltage electronics of the WF280A is optimized for use in mobile phones, smart watches, PDAs, GPS navigation devices and outdoor equipment. The sensor module is housed in a compact 8-pin metal-lid LGA package with a footprint of only 2.0 × 2.5 mm² and 1.0 mm package height. Its small dimensions and its low power consumption allow the implementation in battery driven devices. With a low altitude noise of merely 0.1m and very low offset temperature coefficient (TCO), the WF280A offers superior performance and are perfectly suitable for applications like floor detection, health care as well as GPS refinement. The I²C interface allows for easy system integration with a microcontroller.



Index of Contents

1	Specification	3
2	Absolute maximum ratings	4
3	Operation.....	5
3.1	Brief description	5
3.2	Function description	5
3.3	Measurement of pressure and temperature	6
3.4	Timing of the measurements	7
3.5	Current consumption	8
3.6	Measurement time	8
3.7	Software calculation flow.....	9
3.8	IIR filtering algorithm	9
3.9	Noise.....	10
3.10	Output compensation	11
3.10.1	Calibration coefficients.....	11
3.10.2	Compensation formula.....	12
4	I ² C interface.....	13
4.1	I ² C read status	13
4.2	I ² C read NVM.....	14
4.3	I ² C write.....	14
4.4	I ² C read measurement data	16
4.5	I ² C slave timing	17
5	Global memory map	18
6	Pin-out and connection diagram	20
6.1	Pin-out.....	20
6.2	Connection diagram	21
7	Package, reel and environment	22
7.1	Outline dimensions.....	22
8	Document history and modification.....	23



1 Specification

VDD = 3.3V, T=25°C, unless otherwise noted.

Table 1 Parameter specification

Parameter	Symbol	Condition	Min	Typ	Max	Units
Operating temperature range	T _A	operational	-40	25	+85	°C
		full accuracy	0		65	
Operating pressure range	P	full accuracy	300		1100	hPa
Sensor supply voltage	V _{DD}		1.8		3.6	V
Supply current	I _{DD, LP}	1Hz, lowest osr_p and osr_t		5.4		μA
Peak current	I _{peak}	during pressure measurement		760		μA
Current at temperature measurement	I _{DDT}			541		μA
Sleep current	I _{DDSL}	25°C		0.1	0.3	μA
Relative accuracy	A _{rel}	700...900hPa		±0.12		hPa
		25...40°C		±1.0		m
Offset temperature coefficient	TCO	900hPa		±1.5		Pa/K
		25...40°C		±12.6		cm/K
Absolute accuracy pressure	A _{ext} ^P	300...1100hPa -20...0°C		±1.7		hPa
	A _{full} ^P	300...1100hPa 0...65°C		±1.0		hPa
Resolution of output data in O4 ultra high resolution mode	R ^P	Pressure		0.095		Pa
	R ^T	Temperature		0.01		°C
Noise in pressure	V _{P,full}	Full bandwidth, O4 ultra high resolution		2.0		Pa
				16.6		cm
	V _{P,filtered}	Lowest bandwidth, O4 ultra high resolution		0.2		Pa
				1.7		cm
Absolute accuracy temperature	A ^T	@25°C		±0.5		°C
		0...+65°C		±1.0		°C
PSRR (DC)	PSSR	Full V _{DD} range			±0.005	Pa/mV
Long term stability	ΔPstab	12 months		±TBD		hPa
Solder drifts			-0.5		+2	hPa
Possible sampling	f _{sample}		157	182	TBD	Hz



Parameter	Symbol	Condition	Min	Typ	Max	Units
rate						

2 Absolute maximum ratings

Table 2 Absolute maximum ratings

Parameter	Symbol	Condition	Min	Max	Units
Supply voltage	V _{DD}		-0.3	+3.6	V
Voltage at all IO Pins	V _{DDIO}	all pins	-0.3	V _{DD} +0.3	V
Overpressure	P		0	10,000	hPa
Storage temperature	T _{STOR}		-45	+85	°C
ESD rating	ESD	HBM		±2	kV



3 Operation

3.1 Brief description

The WF280A is designed to be connected directly to an external microcontroller of a mobile device via the I²C bus. The pressure and temperature data has to be compensated by the calibration data of the on-chip Non-Volatile Memory (NVM) which is individually factory calibrated for each device.

3.2 Function description

The WF280A consists of a piezo-resistive micro-machined pressure sensor, an analog to digital converter and a control unit with Non-Volatile Memory (NVM) and a serial I²C interface. The WF280A delivers the uncompensated values of the pressure and the temperature. The individual calibration data are stored in NVM. This is used to compensate sensitivity, offset, temperature dependence and other parameters of the sensor.

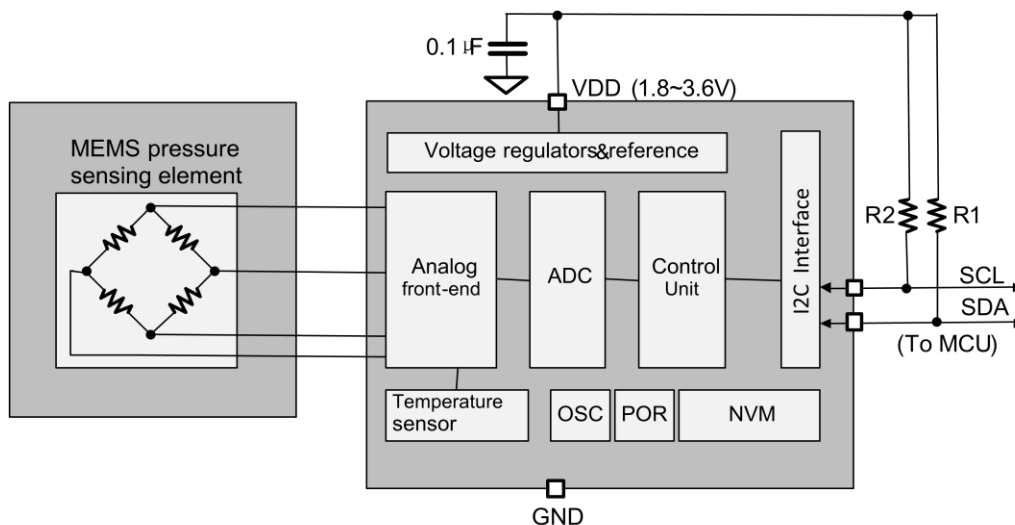


Figure 1 Block diagram of WF280A



3.3 Measurement of pressure and temperature

The microcontroller sends I²C command to start a pressure or temperature measurement. After converting time or checking status via the I²C, the result value (raw pressure data and raw temperature data) can be read via the I²C interface. For pressure and temperature calibration calculation in micro-controller, the calibration data in NVM has to be used. The constants can be read out from the WF280A's NVM via the I²C interface at software initialization.

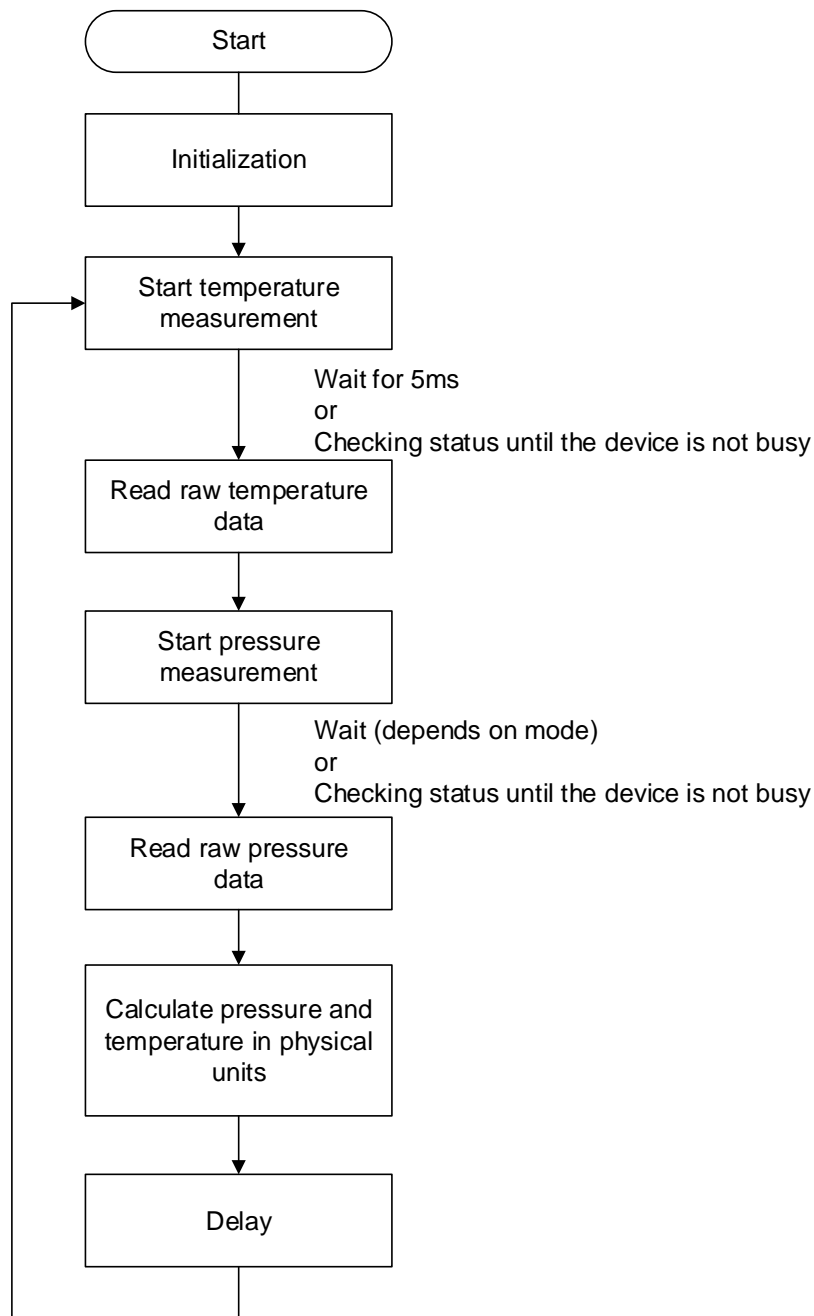


Figure 2 Measurement flow of WF280A



3.4 Timing of the measurements

The output data rate (ODR) of the measurements is controlled by the external micro-controller. A single measurement is performed according to the received I²C command. When the measurement is finished, the sensor returns to sleep mode and the measurement results can be obtained via I²C interface.

The ODR can be increased to about 100 samples per second for dynamic measurement. For application with high ODR, constant t_{delay} is recommended as the self-heating of the pressure sensor and heat dissipation are in the balance if sampling rate is constant, which helps reducing the noise caused by irregular heat exchange between the sensor and the ambient environment. The recommended working timing diagram is shown in Figure 3.

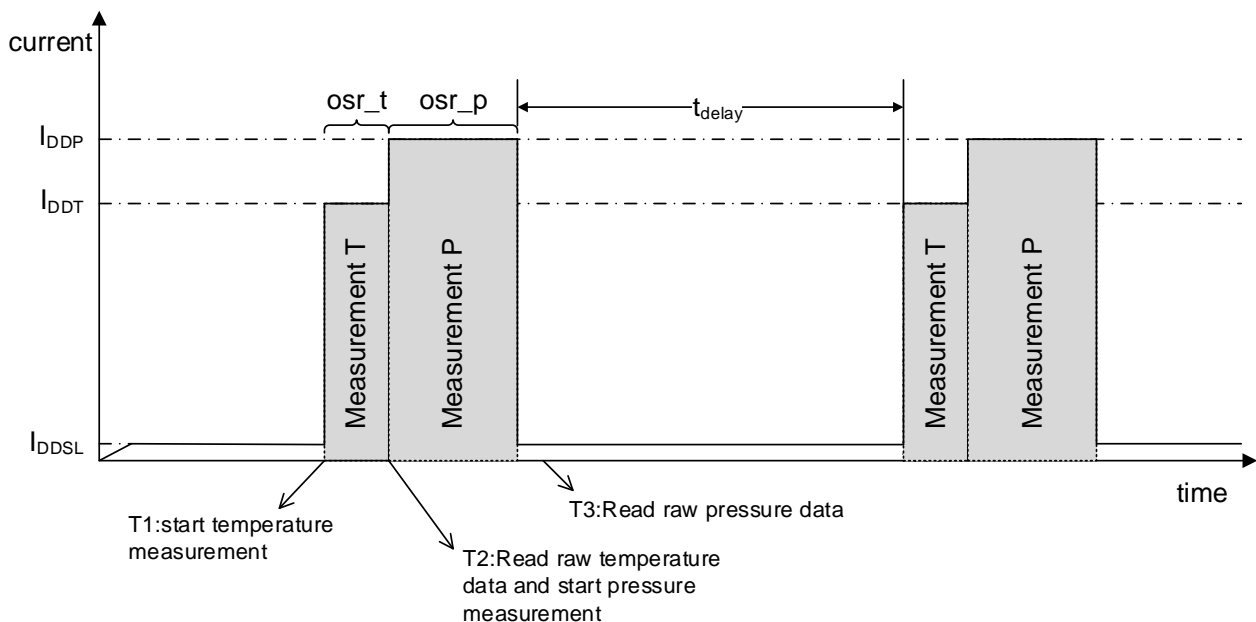


Figure 3 Recommended working timing diagram

For low power consideration, it is sufficient to measure the temperature only once per second and to use this value for all pressure measurements during the same period.

For applications which require low ODR or host-based synchronization, the t_{delay} can be set with any value larger than 0.5ms. The optimum compromise between power consumption, speed and resolution can be selected.



3.5 Current consumption

The current consumption depends on ODR and oversampling setting. The value given below are normalized to an ODR of 1Hz. The actual current consumption at a given ODR can be calculated by multiplying the value Table 3 with the given ODR.

Table 3 Current consumption

Oversampling setting	Pressure oversampling	Temperature oversampling	I _{DD} [μA] @ 1Hz	
			Typ	Max
Ultra low power	x1	x4	5.4	8.2
Low power	x2	x4	6.4	9.7
Standard resolution	x4	x4	9.0	13.7
High resolution	x8	x4	14.1	21.4
Ultra high resolution	x16	x4	24.6	37.4
<i>O2 Ultra high resolution*</i>	x32	x4	45.1	68.6
<i>O4 Ultra high resolution*</i>	x64	x4	86.4	131.3

* "O2/4 Ultra high resolution" are not recommended for dynamic measurement with high ODR. Obvious self-heating phenomenon of the pressure sensor can be observed in these two settings. Ultra high resolution with IIR filter algorithm is recommended in this case.

3.6 Measurement time

The temperature and pressure measurement time depends on oversampling setting *osr_t* and *osr_p*. The following table shows the typical and maximum measurement time based on selected oversampling setting. The minimum achievable frequency is determined by the maximum measurement time.

Table 4 Measurement time

Oversampling setting (Single pressure or temperature)	Measurement time [ms]		Measurement rate [Hz]	
	Typ	Max	Typ	Min
x1	1.92	2.2	520.8	454.5
x2	3.5	4.1	285.7	243.9
x4	6.6	7.7	151.5	129.8
x8	12.7	14.7	78.7	68.0
x16	25.0	29.0	40.0	34.4
x32	49.6	57.6	20.1	17.3



x64	98.7	114.5	10.1	8.7
-----	------	-------	------	-----

3.7 Software calculation flow

When the raw temperature data and raw pressure data are obtained by the MCU, the calculation is performed in the MCU for getting compensated temperature and pressure value in physical units. The simplified software calculation flow is shown in Figure 4.

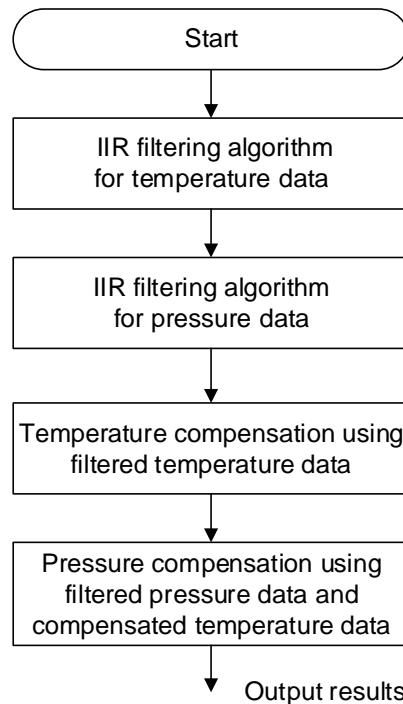


Figure 4 Software calculation flow

Note: Constant t_{delay} is preferred if IIR filtering algorithm is enabled. Please see Figure 3 for the definition of t_{delay} .

3.8 IIR filtering algorithm

For applications where a low noise level is critical, IIR filtering algorithm is strongly recommended if the lower bandwidth is acceptable. By applying IIR filtering algorithm before temperature and pressure compensation, the environmental pressure is subject to many short-term changes can be suppressed, such as slamming of a door or a window, or wind blowing into the sensor. IIR filtering algorithm effectively reduce the bandwidth of the output signals. The formula of the IIR filtering algorithm is as following:

$$\text{data_filtered} = \frac{\text{data_filtered_previous} \cdot (\text{filter_coefficient} - 1) + \text{raw_data_ADC}}{\text{filter_coefficient}}$$



where `data_filtered_previous` is the data coming from the previous `data_filtered`, and `raw_data_ADC` is the raw temperature data or raw pressure data coming from the ADC before IIR filtering. The `filter_coefficient` is an integer range from 0 to 16. It controls the bandwidth of the sensor signal, please see Table 5.

Table 5 Filtering algorithm setting

Filter_coefficient	Bandwidth (ODR is controlled by MCU)
1	Full (Filter off)
2	0.230 × ODR
4	0.092 × ODR
8	0.043 × ODR
16	0.021 × ODR

When IIR filtering algorithm is applied, it is better to keep delay time t_{delay} (see Figure 3) constant to obtain a fixed bandwidth. If temperature measurement is skipped, the corresponding `raw_data_ADC` will be kept unchanged. If `filter_coefficient` is changed during the continuously measurements, an initial operation for IIR filtering algorithm will be performed.

In order to select optimal settings, the following use cases are suggested as shown in Table 6.

Table 6 Recommended filtering setting based on use cases

Use case	Over-sampling setting	osr_p	osr_t	IIR filter coeff.	IDD [μA]	ODR [Hz]	t_{delay} [ms]	RMS Noise [cm]
Handheld device Low-power	Ultra high resolution	×16	×4	4	246	10.0	68	5.8
Handheld device dynamic	Standard resolution	×4	×4	16	630	70	0.5~1	2.5
Weather monitoring	low power	×2	×4	1 (off)	Off	1/60	60000	34.9
Elevator	Standard resolution	×4	×4	4	65.7	7.3	123	8
Drop detection	Low power	×2	×4	1 (off)	576	90	0.5~1	34.9
Indoor navigation	Ultra high resolution	×16	×4	16	647	26.3	6.4	1.6

3.9 Noise

Both pressure and temperature noise depend on the oversampling and IIR filter coefficient



settings selected.

Table 7 Noise in pressure

Typical RMS noise in pressure [Pa]					
Oversampling setting	Off	2	4	8	16
Ultra low power	6.0	2.9	1.7	1.0	0.7
Low power	4.2	2.5	1.3	0.7	0.4
Standard resolution	3.5	1.5	1.0	0.5	0.3
High resolution	2.8	1.3	0.9	0.4	0.2
Ultra high resolution	2.2	1.2	0.7	0.3	0.2
O2 Ultra high resolution	2.0	1.1	0.5	0.3	0.2
O4 Ultra high resolution	TBD	TBD	TBD	0.3	0.2

Table 8 Noise in temperature

Typical RMS noise in temperature [°C]	
Temperature oversampling	IIR filter off
oversampling x4	0.007
oversampling x8	0.006
oversampling x16	0.005
oversampling x32	0.004

3.10 Output compensation

The WF280A output consists of the ADC output values include raw temperature and pressure data. Due to different characteristic of each sensing element, the actual pressure and temperature must be calculated using a set of calibration coefficients. These coefficients are individually factory calibrated and stored in the NVM. The NVM is organized with 16-bit data type.

3.10.1 Calibration coefficients

The NVM contains 11 calibration coefficients in total. Calibration coefficients are named co_t1~co_t3 for temperature compensation related values and co_p1~co_p8 for pressure compensation related values. The mapping is shown in Table 9.



Table 9 Calibration coefficients storage in NVM

Addr.	Bit	Calibration coefficients	Addr.	Bit	Calibration coefficients
0x03	15	co_p8[16]	0x08	15:0	co_p5[15:0]
	14	reserved	0x09	15:0	co_p7[15:0]
	13:12	co_p3[25:24]	0x0A	15:0	co_p6[15:0]
	11:10	co_p6[25:24]	0x0B	15:0	co_p3[15:0]
	9:8	co_p7[25:24]	0x0C	15:0	co_t2[15:0]
	7:6	co_p5[25:24]	0x0D	15:0	co_t1[15:0]
	5:4	co_p4[25:24]	0x0E	15:0	co_t3[15:0]
	3:2	co_p1[25:24]	0x0F	15:0	co_p8[15:0]
1:0	co_p2[25:24]	0x10	15:8	co_p2[23:16]	
0x04	15:6		reserved	7:0	co_p1[23:16]
	5:4	co_t2[17:16]	0x11	15:8	co_p4[23:16]
	3:2	co_t3[17:16]		7:0	co_p5[23:16]
	1:0	co_t1[17:16]	0x12	15:8	co_p6[23:16]
0x05	15:0	co_p2[15:0]		7:0	co_p7[23:16]
0x06	15:0	co_p1[15:0]	0x13	15:8	co_p3[23:16]
0x07	15:0	co_p4[15:0]		7:0	reserved

3.10.2 Compensation formula

The ODR and OSR can be selected by selected by the oversampling_setting in the C code. The IIR filter coefficient can also be set in the C code.

Using the driver C code provided by WF Technologies is strongly recommended. Please contact with WF Technologies for details.



4 I²C interface

The I²C slave interface is compatible with Philips I²C specification. Standard and fast mode are supported. SDA and SCL are not pure open-drain. Both pads contain ESD protection diodes to VDD and GND. As the device does not perform clock stretching, the SCL structure is a high-Z input without drain capability.

The 7-bit device address is 1111000 (0x78). By programming the low 7bits of the 3rd data byte of NVM (address 0x02), see Table 14, the device address can be redefined.

4.1 I²C read status

Whenever the device is addressed in read mode (RW = '1') at address 11110001, the status byte is always the first output byte. For checking the status of the device, the I²C master must send NOACK and stop condition after the status byte, as shown in Figure 5.

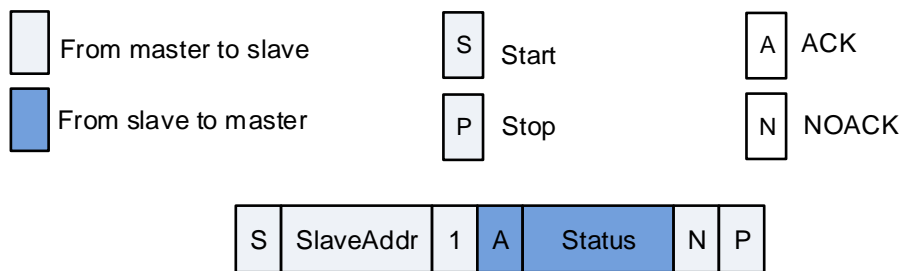


Figure 5 I²C read status

The status byte provides the information of the device. The information of each bit of the status byte is described in Table 10.

Table 10 Status byte

Status	Meaning	Description
Bit7	Reserved	Constant 0
Bit6	Power indication	"1" ADC is powered on; "0" ADC is powered off
Bit5	Busy indication	"1" Busy: The device is measuring pressure and temperature and the results are not ready yet. New I ² C command will not be proceeded. "0" Idle: The recent I ² C command has been executed and the data to be read is ready.
Bit4	Reserved	Constant 0
Bit3	Mode Status	"0" normal mode "1" test mode, only for testing
Bit2	Memory integrity/error	"0" The integrity check (CRC) of the NVM is passed.



Status	Meaning	Description
	flag	All the data in the NVM is correct. “1” The integrity check(CRC) of the NVM is failed. Some of the data in the NVM is error.
Bit1	Reserved	Constant 0
Bit0	Reserved	Constant 0

4.2 I²C read NVM

The NVM has a width of 16 bits. To read the 16-bit data from the NVM, first the address of the NVM must be sent in the write mode (I²C slave address 11110000). Then wait for at least 80µs. After this the data is ready, the slave is addressed in read mode (RW = ‘1’) at address 11110001, after which the slave sends out status byte firstly followed with two bytes data until a NOACK and stop condition occurs, as shown in Figure 6.

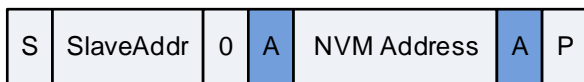


Figure 6 I²C read NVM

4.3 I²C write

The pressure or temperature measurement is triggered by sending the command in write mode, which is done by sending the slave address in write mode (RW = ‘0’), resulting in slave address 11110000. Then the master sends the command byte and the 16-bit command data. The transaction is ended by a stop condition, as shown in Figure 7.



Figure 7 I²C write command

The detail of the I²C command and command data is described in Table 11.

Table 11 I²C commands

CMD, Data(HEX)	Measurement	Analog Front End Configuration
0xA0, 0x0000	Pressure measurement	AFE is configured by the



CMD, Data(HEX)	Measurement	Analog Front End Configuration
		pre-programmed setting in the NVM (address 0x14).
0xA1, 0xssss	Pressure measurement	AFE is configured by 0xssss, see data content and format in the NVM(address0x14)
0xA2, 0x0000	Pressure measurement with system auto-zero	AFE is configured by the pre-programmed setting in the NVM (address 0x14).
0xA3, 0xssss	Pressure measurement with system auto-zero	AFE is configured by 0xssss, see data content and format in the NVM(address0x14)
0xA4, 0x0000	Temperature measurement	AFE is configured by the pre-programmed setting in the NVM (address 0x14).
0xA5, 0xssss	Temperature measurement	AFE is configured by 0xssss, see data content and format in the NVM(address0x14)
0xA6, 0x0000	temperature measurement with system auto-zero	AFE is configured by the pre-programmed setting in the NVM (address 0x14).
0xA7, 0xssss	temperature measurement with system auto-zero	AFE is configured by 0xssss, see data content and format in the NVM(address0x14)

The format and purpose of configuration bits “0xssss” is the same with the definitions of the 16-bit data byte in the NVM with the address 0x14. System auto-zero mentioned in Table 11 is used for measuring the inherent system offset for the respective configuration which is only used in the software initialization process. The detail of the format is shown in Table 12.

Table 12 AFE setting format

Analog front end configuration format (ssss)		
Bit	Description	Definition
15:14	osr_t	Oversampling setting of temperature measurement 00 : x4 10 : x16 01 : x8 11 : x32
13:11	osr_p	Oversampling setting of pressure measurement 111 : x0 011 : x8 110 : x1 010 : x16 101 : x2 001 : x32



Analog front end configuration format (ssss)		
		100 : x4 000 : x64
10:8	A2D_Offset	ADC offset and resulting A2D input range 000 : 1/16 → [-1/16, 15/16] (Default value) 001 : 2/16 → [-2/16, 14/16] 010 : 3/16 → [-3/16, 13/16] 011 : 4/16 → [-4/16, 12/16] 100 : 5/16 → [-5/16, 11/16] 101 : 6/16 → [-6/16, 10/16] 110 : 7/16 → [-7/16, 9/16] 111 : 8/16 → [-8/16, 8/16] <i>Use the default value is recommended.</i>
7:6	Clk_divider	ADC sampling clock frequency setting Use "00" is recommended.
5	Gain_polarity	Polarity of pre-amplifier for measuring pressure 0 : negative 1 : positive
4:2	Gain_stage2	Gain setting for the 2nd pre-amplifier stage 000 : 1.1x 100 : 1.5x 001 : 1.2x 101 : 1.6x 010 : 1.3x 110 : 1.7x 011 : 1.4x 111 : 1.8x
1:0	Gain_stage1	Gain setting for the 1st pre-amplifier stage 00 : 12x 10 : 30x 01 : 20x 11 : 40x

4.4 I²C read measurement data

After the pressure or temperature measurement is triggered by sending relative I²C commands described in 4.3, WF280A starts a measurement and puts the result in the output buffer. Depend on the OSR setting, the measurement will complete in several milliseconds, as shown in Table 4. Then the I²C master can read the pressure or temperature raw data. User can also regularly read the status via I²C to check the device is in busy or idle. The measurement is ready for reading if the status is idle.

Pressure measurement data is always read in 24-bit format, as shown in Figure 8.

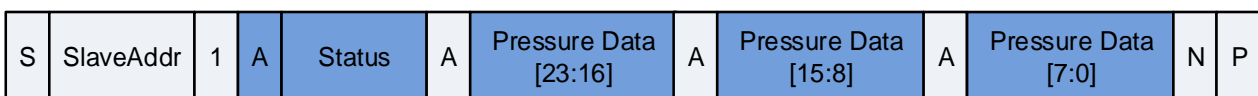


Figure 8 I²C read pressure data

Temperature measurement data can be read in 16-bit or 24-bit format depends on the



resolution requirement of the application. For pressure compensation calculation, high 16-bit temperature data is enough.

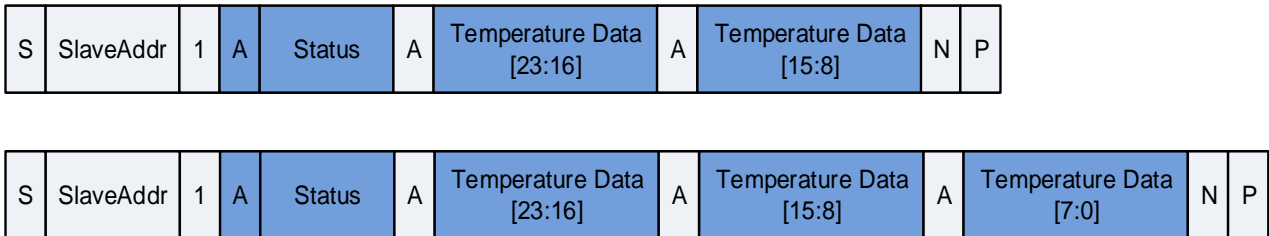


Figure 9 I²C read temperature data

4.5 I²C slave timing

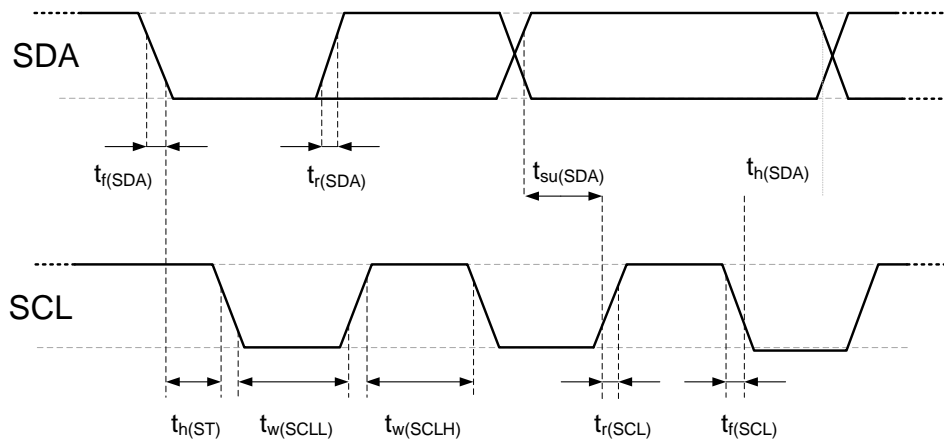


Figure 10 I²C timing diagram

Table 13 I²C timing

Symbol	Parameter	I ² C standard mode		I ² C fast mode		Unit
		Min	Max	Min	Max	
$f_{(SCL)}$	SCL clock frequency	0	100	0	400	kHz
$t_{w(SCLL)}$	SCL clock low time	4.7		1.3		μ s
$t_{w(SCLH)}$	SCL clock high time	4.0		0.6		μ s
$t_{su(SDA)}$	SDA setup time	250		100		ns
$t_{h(SDA)}$	SDA data hold time	0.09	3.45	0.02	0.9	μ s

Notes: Measurement points are done at 0.2 V_{DD} and 0.8 V_{DD}, for both ports.



5 Global memory map

The Non-volatile memory has a width of 16 bits. There are several memory which are reserved; they should not be written to, otherwise the CRC bit in the status would not be correct. The detail of the memory is given in Table 14.

Table 14 Memory map

NVM Addr (HEX)	Bit Range	Default Value	Description	Notes/Explanations
0x00	15:0	0x0000	cust_ID0	Custom ID byte 0
0x01	15:0	0x0000	cust_ID1	Custom ID byte 1
0x02	15:7	0x000	-	Reserved
	6:0	0x00	slave_Addr	I ² C slave address; valid 0x01~0x7F. If slave_addr=0x00, then 0x78 is used. Note: address codes 0x04 to 0x07 are reserved for entering I ² C High Speed Mode.
0x03	15	Individual	co_p8[16]	Bit [16] of calibration coefficient co_p8
	14	0x0	reserved	reserved
	13:12	Individual	co_p3[25:24]	Bits [25:24] of calibration coefficient co_p3
	11:10	Individual	co_p6[25:24]	Bits [25:24] of calibration coefficient co_p6
	9:8	Individual	co_p7[25:24]	Bits [25:24] of calibration coefficient co_p7
	7:6	Individual	co_p5[25:24]	Bits [25:24] of calibration coefficient co_p5
	5:4	Individual	co_p4[25:24]	Bits [25:24] of calibration coefficient co_p4
	3:2	Individual	co_p1[25:24]	Bits [25:24] of calibration coefficient co_p1
0x04	1:0	Individual	co_p2[25:24]	Bits [25:24] of calibration coefficient co_p2
	15:6	0x000	reserved	reserved
	5:4	Individual	co_t2[17:16]	Bits [17:16] of calibration coefficient co_t2
	3:2	Individual	co_t3[17:16]	Bits [17:16] of calibration coefficient co_t3
0x05	1:0	Individual	co_t1[17:16]	Bits [17:16] of calibration coefficient co_t1
	15:0	Individual	co_p2[15:0]	Bits [15:0] of calibration coefficient co_p2
0x06	15:0	Individual	co_p1[15:0]	Bits [15:0] of calibration coefficient co_p1
0x07	15:0	Individual	co_p4[15:0]	Bits [15:0] of calibration coefficient co_p4
0x08	15:0	Individual	co_p5[15:0]	Bits [15:0] of calibration coefficient co_p5
0x09	15:0	Individual	co_p7[15:0]	Bits [15:0] of calibration coefficient co_p7
0x0A	15:0	Individual	co_p6[15:0]	Bits [15:0] of calibration coefficient co_p6
0x0B	15:0	Individual	co_p3[15:0]	Bits [15:0] of calibration coefficient co_p3
0x0C	15:0	Individual	co_t2[15:0]	Bits [15:0] of calibration coefficient co_t2
0x0D	15:0	Individual	co_t1[15:0]	Bits [15:0] of calibration coefficient co_t1
0x0E	15:0	Individual	co_t3[15:0]	Bits [15:0] of calibration coefficient co_t3
0x0F	15:0	Individual	co_p8[15:0]	Bits [15:0] of calibration coefficient co_p8
0x10	15:8	Individual	co_p2[23:16]	Bits [23:16] of calibration coefficient co_p2



WF280A
Digital Pressure Sensor
Data Sheet

NVM Addr (HEX)	Bit Range	Default Value	Description	Notes/Explanations
	7:0	Individual	co_p1[23:16]	Bits [23:16] of calibration coefficient co_p1
0x11	15:8	Individual	co_p4[23:16]	Bits [23:16] of calibration coefficient co_p4
	7:0	Individual	co_p5[23:16]	Bits [23:16] of calibration coefficient co_p5
0x12	15:8	Individual	co_p6[23:16]	Bits [23:16] of calibration coefficient co_p6
	7:0	Individual	co_p7[23:16]	Bits [23:16] of calibration coefficient co_p7
0x13	15:8	Individual	co_p3[23:16]	Bits [23:16] of calibration coefficient co_p3
	7:0	0x00	reserved	reserved
0x14	15:14	0x00	osr_t	Default oversampling setting of temperature measurement
	13:11	0x00	osr_p	Default oversampling setting of pressure measurement
	10:8	0x0	A2D_Offset	ADC offset and resulting A2D input range
	7:6	0x0	Clk_divider	ADC sampling clock frequency setting
	5	0x1	Gain_polarity	Polarity of pre-amplifier for measuring pressure
	4:2	Individual	Gain_stage2	Gain setting for the 2nd pre-amplifier stage
	1:0	Individual	Gain_stage1	Gain setting for the 1st pre-amplifier stage
0x15~ 0x1E	15:13	0x0000	Reversed	Reserved
0x1F	15:0	Individual	ChecksumC	Integrity checksum (CRC)



6 Pin-out and connection diagram

6.1 Pin-out

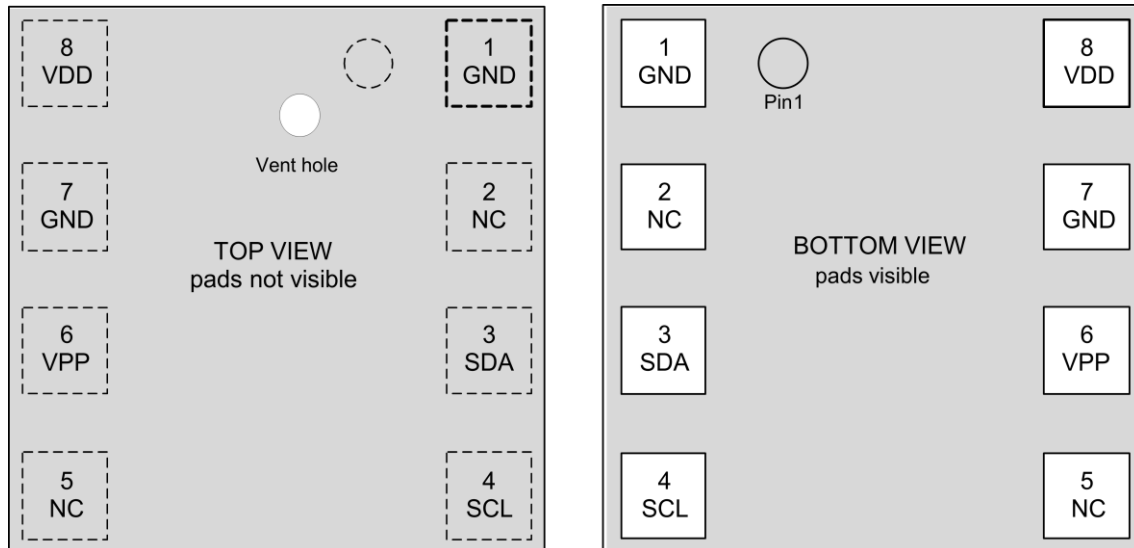


Figure 11 Pin-out top and bottom view

Table 15 Pin description

Pin	Name	I/O Type	Description	Connect to
1	GND	Supply	Ground	GND
2	NC	--	Not Connected	Not connected
3	SDA	In/Out	Serial data input and output	I ² C SDA
4	SCL	In	Serial clock input	I ² C SCL
5	NC	--	Not Connected	Not connected
6	VPP	Supply	NVM programming supply	Not connected
7	GND	Supply	Ground	GND
8	VDD	Supply	Power supply	VDD



6.2 Connection diagram

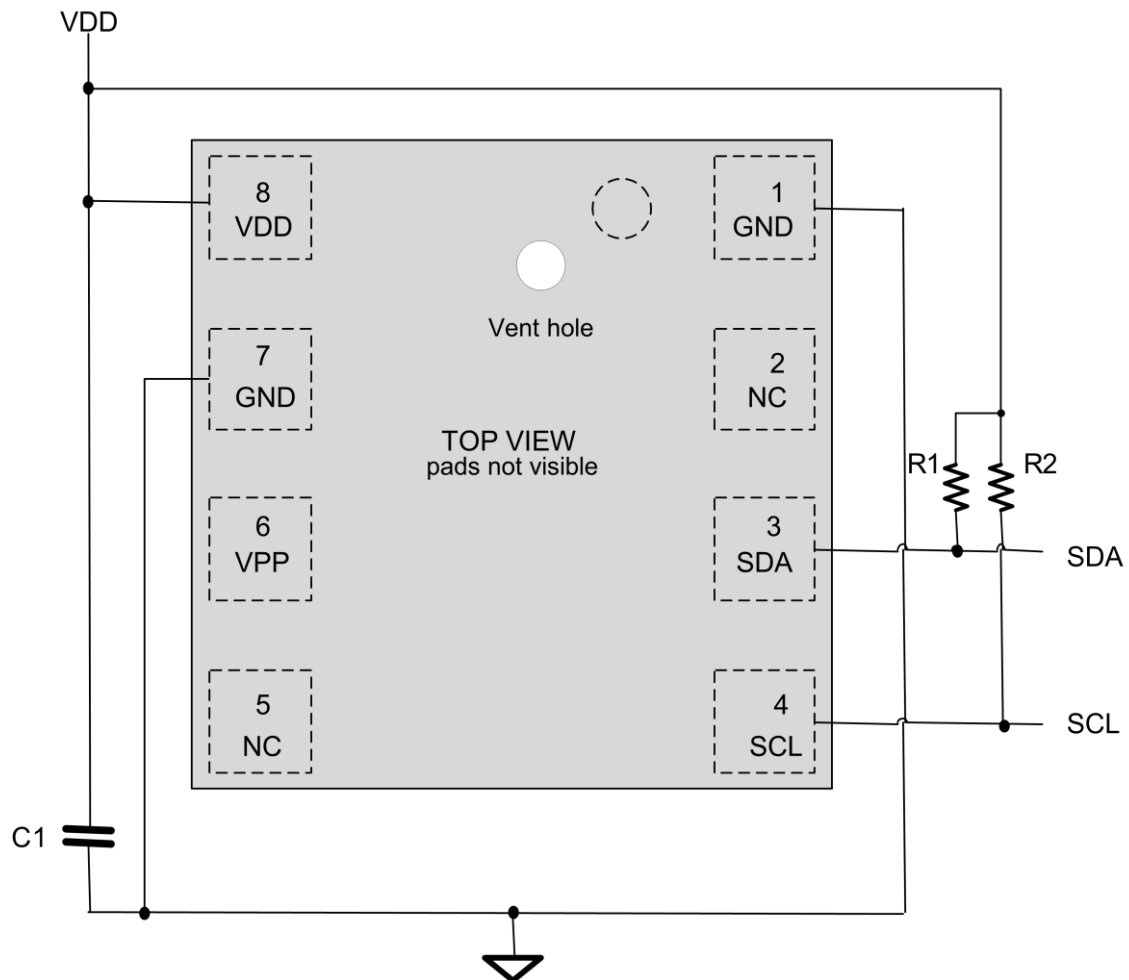


Figure 12 Connection diagram

Notes:

- The recommended value for C1 is 100nF
- The value for the pull-up resistors R1, R2 should be based on the interface timing and the bus load; the typical value is 4.7 k Ω for both resistors.



7 Package, reel and environment

7.1 Outline dimensions

The sensor housing is an 8-pin metal-lid LGA 2.0 × 2.5 × 0.95 mm³ package. Its dimensions are depicted in Figure 13.

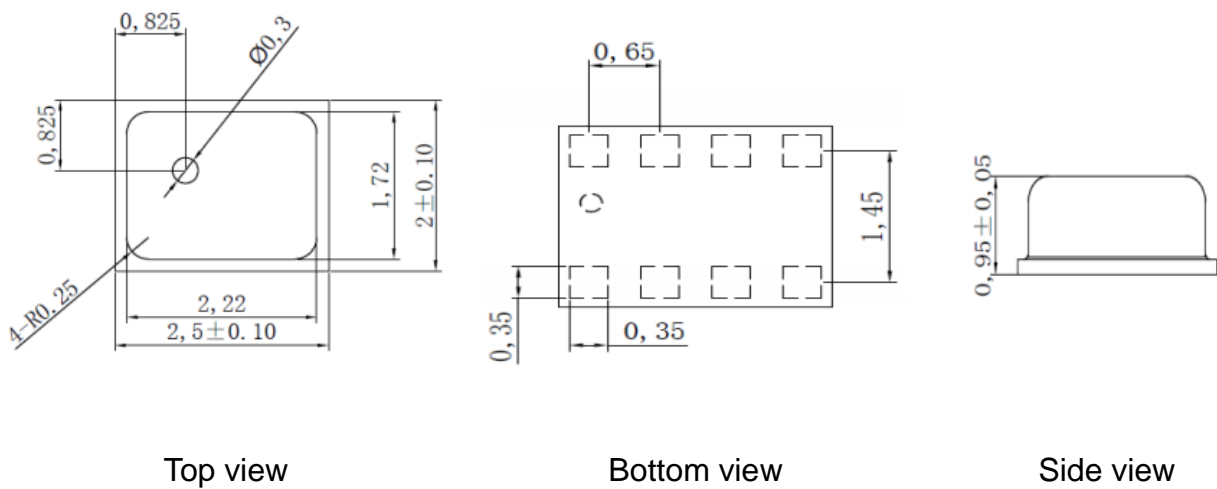


Figure 13 Package outline dimensions for top, bottom and side view



8 Document history and modification

Version	Description	Date
1.0	Initial release	Jul. 20, 2015
2.0	Correct VDD&VPP definition, modify value of pull up resisters	Mar. 20, 2016
2.2	Updated	Jan. 8 , 2024